

ABSTRACT

Various embodiments of the invention related to an integrated lid and test device for a socket, such as a land grid array (LGA) socket, that functions as a lid, as a testing device, and/or as a pick and place lid. Specifically, the integrated lid may provide test capability, in manufacturing of the socket and/or a printed circuit board (PCB) such as a motherboard, onto which the socket is attached. Thus the integrated lid may allow for testing the socket and/or the PCB for correct assembly and connectivity without requiring removal of the integrated lid to insert a test device prior to testing, or removal of a test device and replacement of the lid after testing.